

Notice of References Cited	Application/Control No. 10/614,132		Applicant(s)/Patent Under Reexamination SOMAYAJI ET AL.	
	Examiner Leigh Marie Garbowski		Art Unit 2825	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,742,167	05-2004	Grau, Gunter	716/4
	C	US-2004/0194043	09-2004	Sundar et al.	716/005
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	E	US-6,826,517	11-2004	Okada, Takako	703/2
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	H	US-6,397,171	05-2002	Belk, Nathan R.	703/14
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagaraj et al., "A Practical Approach to Static Signal Electromigration Analysis," 1998 ACM/DAC, pages 572-577.
	V	Donohoe et al., "Simple Edge Basis Functions for Open-Ended Bodies of Revolution," 1995 IEEE, pages 329-332.
	W	Ting et al., "AC Electromigration Characterization and Modeling of Multilayered Interconnects," 1993 IEEE/IRPS, pages 311-316.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.